## Notice of References Cited Application/Control No. 10/625,900 Examiner Robert Beatty Applicant(s)/Patent Under Reexamination KIM ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,665,515	12-2003	Lee, Kyung-woo	399/330
	В	US-6,628,917	09-2003	Lee, Kyung-woo	399/330
	С	US-6,580,896	06-2003	Lee, Kyung-woo	399/330
	D	US-6,571,080	05-2003	Lee et al.	399/330
	E	US-5,426,495	06-1995	Sawamura et al.	399/331
	F	US-6,096,995	08-2000	Toyota et al.	219/216
	G	US-6,072,979	06-2000	Hiroaka, Yuji	399/330
	Н	US-6,072,156	06-2000	Matsuo et al.	219/216
	1	US-4,284,875	08-1981	Namiki et al.	219/216
	J	US-6,512,913	01-2003	Hirst et al.	399/328
	к	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 09166931 A	06-1997	Japan	DOMOTO et al.	G03G 15/20
	0	JP 54092750 A	07-1979	Japan	NAMIKI, RYOICHI	G03G 15/20
	Р	JP 54056448 A	05-1979	Japan	NAMIKI et al.	G03G 15/20
	Q	WO 02/31601 A1	04-2002	PCT	Landa et al.	G03G 15/20
	R	EP 1217466 A1	06-2002	European Patent	LEE, KYUNG-WOO	G03G 15/20
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	٧					
	w					
	х					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYYY format are publication dates. Classifications may be US or foreign.